

IRFM220B

200V N-Channel MOSFET

General Description

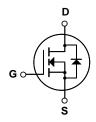
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, DC-AC converters for uninterrupted power supply and motor control.

Features

- 1.13A, 200V, $R_{DS(on)}$ = 0.8 Ω @V_{GS} = 10 V Low gate charge (typical 12 nC)
- Low Crss (typical 10 pF)
- Fast switching
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		IRFM220B	Units
V _{DSS}	Drain-Source Voltage		200	V
I _D	Drain Current - Continuous (T _C = 25	°C)	1.13	А
	- Continuous (T _C = 70	°C)	0.9	А
I _{DM}	Drain Current - Pulsed	(Note 1)	9.0	А
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	65	mJ
I _{AR}	Avalanche Current	(Note 1)	1.13	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	0.24	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		2.4	W
	- Derate above 25°C		0.019	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		52	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	3	Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		-	0.2		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V				10	μΑ
		V _{DS} = 160 V, T _C = 125°C)	-		100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$		1		-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 0.57 \text{ A}$			0.65	0.8	Ω
9FS	Forward Transconductance	V _{DS} = 40 V, I _D = 0.57 A	(Note 4)		1.6		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			300 50	390 65	pF pF
C _{oss}	Output Capacitance				50	65	pF
C _{rss}	Reverse Transfer Capacitance				10	13	pF
Switchi	ing Characteristics						
t _{d(on)}	Turn-On Delay Time	V 400 V I 50 A			6.8	24	ns
t _r	Turn-On Rise Time	$V_{DD} = 100 \text{ V}, I_{D} = 5.0 \text{ A},$ $R_{G} = 25 \Omega$			45	100	ns
t _{d(off)}	Turn-Off Delay Time	NG = 20 32			30	70	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		40	90	ns
Qg	Total Gate Charge	V _{DS} = 160 V, I _D = 5.0 A,		-	12	16	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		-	2.0		nC
Q _{gd}	Gate-Drain Charge	(Note 4,		-	5.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Rating	S				
I _S	Maximum Continuous Drain-Source Did	<u> </u>				1.13	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	Pulsed Drain-Source Diode Forward Current				9.0	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.13 A				1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 5.0 \text{ A},$			130		ns
Q _{rr}	Reverse Recovery Charge	$dI_{F}/dt = 100 \text{ A/}\mu\text{s} \qquad \text{(Note 4)}$			0.58		μС

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 76mH, I_{AB} = 1.13A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} ≤ 5.0A, di/dt < 300A/µs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

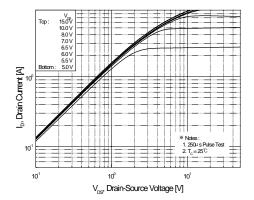
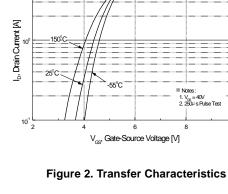


Figure 1. On-Region Characteristics



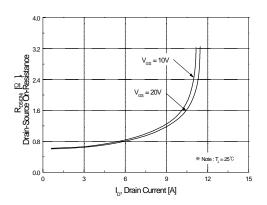


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

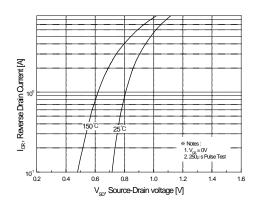


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

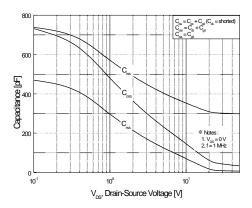


Figure 5. Capacitance Characteristics

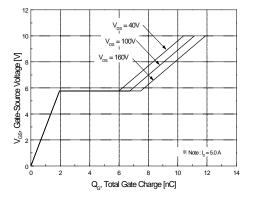
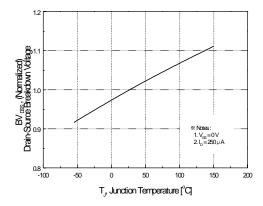


Figure 6. Gate Charge Characteristics

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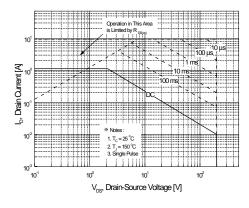
Typical Characteristics (Continued)



25 (000) 20 (000) 150 (000

Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



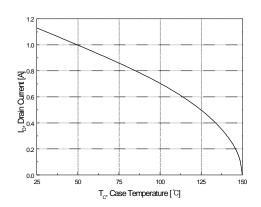


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

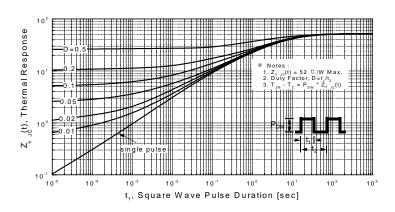
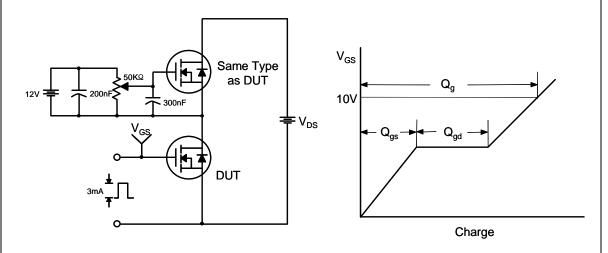
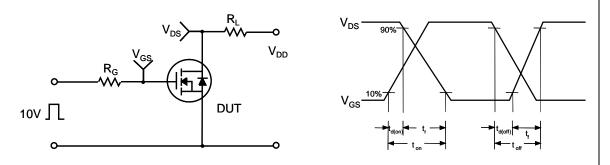


Figure 11. Transient Thermal Response Curve

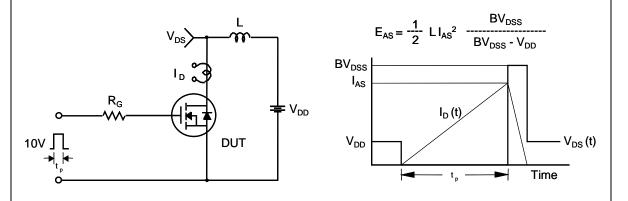
Gate Charge Test Circuit & Waveform



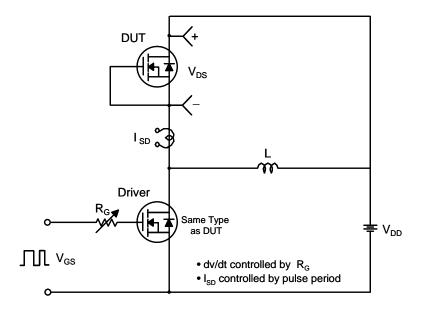
Resistive Switching Test Circuit & Waveforms

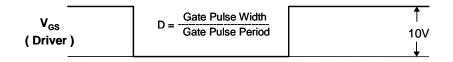


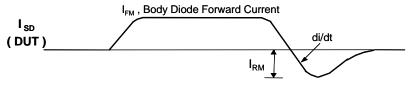
Unclamped Inductive Switching Test Circuit & Waveforms



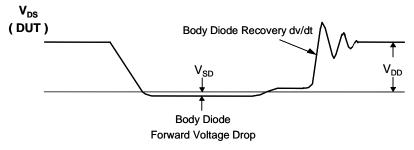
Peak Diode Recovery dv/dt Test Circuit & Waveforms







Body Diode Reverse Current



Package Dimensions SOT-223 0.65 ± 0.20 3.00 ± 0.10 MAX1.80 1.75 ±0.20

(0.60)

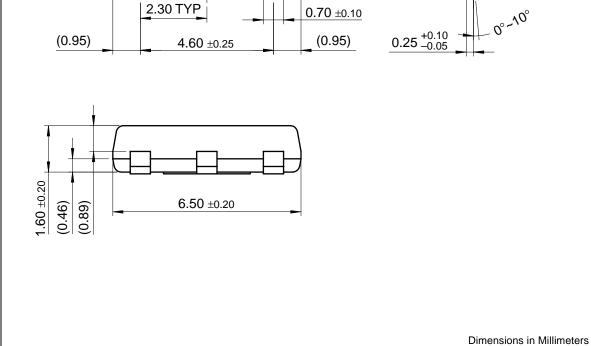
(0.60)

0.06 +0.04 -0.02

7.00 ±0.30

 3.50 ± 0.20

0.70 ±0.10



2.30 TYP

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